Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
	4	(("20040100246") or ("5796751")).PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/07/11 09:07
S2	-	de-19845409-\$.did.	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	NO	2005/07/11 09:09
S3	2	ep-994361-\$.did.	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	Z O	2005/07/11 09:08
\$2	386	(324/76.82.ccls.) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 09:19
SS	1361	(324/76.77,76.11.ccls.) and @ad<"20030810"	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 10:21
9S	2	S4 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) same (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/11 09:42
S7	-	S5 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) same (parameter near\$ (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/11 09:59

US-PGPUB; OR ON 2005/07/11 13:20 USPAT; EPO; JPO; DERWENT : IBM_TDB	US-PGPUB; OR 2005/07/11 09:58 USPAT; EPO; JPO; DERWENT ; IBM_TDB	US-PGPUB; OR ON 2005/07/12 10:07 USPAT; EPO; JPO; DERWENT ; IBM_TDB	US-PGPUB; OR ON 2005/07/11 13:25 USPAT; EPO; JPO; DERWENT ; IBM_TDB	US-PGPUB; OR ON 2005/07/11 14:27 USPAT; EPO; JPO; DERWENT ; IBM_TDB	US-PGPUB; OR ON 2005/07/12 09:13 USPAT; EPO; JPO; DERWENT ; IBM_TDB	US-PGPUB; OR ON 2005/07/11 13:58 USPAT; EPO; JPO; DERWENT ; IBM_TDB	US-PGPUB; OR ON 2005/07/11 13:33 USPAT; EPO; JPO; DERWENT
(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) same (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))	S8 and @ad<"20030810" [S9 and counter same ((state mode status) near3 (IC (integrated adj circuit) \$6chip (LASIC)) EASIC))	S9 and (external near2 connect\$5) near3 (IC (integrated adj circuit) \$6chip ASIC) Each	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) same (parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) and @ad<"20030810"	S12 and ((check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 record\$5 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) near3 voltage near3 (change variation difference))	S13 and (external near2 connect\$5) near3 (IC (integrated adj circuit) \$6chip ASIC) [1]	S13 and (anal\$5 adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) near3 (IC (integrated adj circuit) \$6chip ASIC)
2894	2503	21	42	2503	122	E	7
8S	6S	S10	SIII	S12	S13	S14	S15

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S13 and (a section stat (integrated		US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	go g	NO Z	2005/07/11 13:46
(anal\$5 adj2 (assembly unit means module set instrumer circuit) \$6chip ASIC) near3	(anal\$5 adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) near5 (IC (integrated adj U circuit) \$6chip ASIC) near3 (external near2 connect\$5) and @ad<"20030810"	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	š	Z O	2005/07/11 13:53
(((analysis analyzing analyzi machine mechanism section cell)) analyzer analyser) nea @ad<"20030810"	(((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) near5 (IC (integrated adj circuit) \$6chip ASIC) and	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/11 16:09
S18 and (external near2 con	S18 and (external near2 connect\$5) near3 (IC (integrated adj circuit) \$6chip ASIC) U EB D D	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/11 13:59
(((analysis analyzing analyze machine mechanism section cell)) analyzer analyser) nea @ad<"20030810"	(((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment U cell)) analyzer analyser) near3 (IC (integrated adj circuit) \$6chip ASIC) and	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO O	2005/07/11 13:58
S20 and (external near2 conn	S20 and (external near2 connect\$5) near3 (IC (integrated adj circuit) \$6chip ASIC) U U D D	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/11 13:59
(check\$3 detect\$3 sens\$3 me determin\$3 recogniz\$3 inspe meter\$5) same (parameter ne	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) same (parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) and \$19 D D D	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO O	2005/07/11 14:18
(check\$3 detect\$3 sens\$3 me: determin\$3 recogniz\$3 inspec meter\$5) near3 (parameter ne @ad<"20030810"	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) near3 (parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) and D@ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/11 14:39

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4	64	S23 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) near5 (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 09:13
1		(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) near3 (parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 14:24
4	9	S25 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) near5 (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 09:16
	w	S26 and ((check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) near3 voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 09:14
	0	(((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) near5 (IC (integrated adj circuit) \$6chip ASIC) same (((check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) near3 voltage near3 (change variation difference)))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 10:12
	∞	S28 and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 09:42
(-	70	S25 and counter same (state mode status)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 09:34

S31	0	S30 and counter same (digital\$3 near3 cod\$3)	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 09:35
S32	0	S25 and counter same (digital\$3 near3 cod\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 09:45
S33	4	S25 and (parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) same (digital\$3 near3 cod\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; BM_TDB	OR	NO	2005/07/12 09:49
S34	_	counter same (parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) same (digital\$3 near3 cod\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 14:32
S35	1229	(counter same ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 09:45
S36	12	S35 and counter same (digital\$3 near3 cod\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 09:51
S37		S36 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) near3 (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 09:53
S38	279	S35 and counter same digital\$3	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 09:46

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839	0	S38 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) near3 (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 09:47
S40	10	((parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) same (digital\$3 near3 cod\$3)) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO O	2005/07/12 09:53
S41	78	S35 and counter same ((digital\$3 binary) near3 cod\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; BM_TDB	OR	NO	2005/07/12 09:52
S42		S41 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identit\$7 record\$5 meter\$5) near3 (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	NO O	2005/07/12 09:53
S43	0	S40 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 14:26
S44	85	S25 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 10:28
S45	4	S44 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) near5 (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 10:38
S46 ·	1229	(324/76.16,73.1.ccls.) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 10:22

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2005/07/12 10:22	2005/07/12 10:24	2005/07/12 10:25	2005/07/12 10:26	2005/07/12 10:30	2005/07/12 10:31	2005/07/12 10:34	2005/07/12 10:36
ZO	NO CO	NO	NO NO	NO	NO	NO NO	ZO
OR	OR	OR	OR	OR	OR	OR	OR
US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	US-PGPUB; USPAT; EPO; PO; DERWENT ; IBM_TDB	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	USPAT; USPAT; EPO; IPO; DERWENT ; IBM_TDB	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	USPAT; USPAT; EPO; IPO; DERWENT ; IBM_TDB	USPAT; USPAT; EPO; JPO; DERWENT ; IBM_TDB
(324/763,765.ccls.) and @ad<"20030810"	(324/158.1.ccls.) and @ad<"20030810"	(714/724,726.ccls.) and @ad<"20030810"	(702/127.ccls.) and @ad<"20030810"	S46 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	S47 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	S48 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	S49 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))
4347	4544	3981	259	106	435	250	93
S47	S48	. 849	850	S51	S52	S53	S54

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2005/07/12 14:26	2005/07/12 10:59	2005/07/12 11:03	2005/07/12 11:22	2005/07/12 11:23	2005/07/12 10:45	2005/07/13 07:39	2005/07/13 08:57
Zo Co	Z _O	NO	NO	NO NO	NO	NO	NO
OR	SO .	OR	OR	OR	OR	OR	NO .
US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	USPAT; USPAT; EPO; JPO; DERWENT ; IBM_TDB	USPAT; USPAT; EPO; IPO; DERWENT ; IBM_TDB	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	USPAT; USPAT; EPO; IPO; DERWENT ; IBM_TDB	USPAT; USPAT; EPO; IPO; DERWENT ; IBM_TDB	USPAT; USPAT; EPO; IPO; DERWENT ; IBM_TDB	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB
S50 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identit\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	S51 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) with (IC (integrated adj circuit) \$6chip ASIC)	S52 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) with (IC (integrated adj circuit) \$6chip ASIC)	S53 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) with (IC (integrated adj circuit) \$6chip ASIC)	S54 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) with (IC (integrated adj circuit) \$6chip ASIC)	S55 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) with (IC (integrated adj circuit) \$6chip ASIC)	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) near3 (operat\$5 near1 parameter) and @ad<"20030810"	S61 and (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))
10	N	19	v	2	0	17828	210
S55	S56	S57	S58	S29	098	S61	S62

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S63	45	S62 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 08:59
S64	14	S63 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 08:59
S9S		S64 and counter same (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 14:33
S66	176	S61 and ((operat\$5 near1 parameter) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO O	2005/07/12 16:35
292	32	S66 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/12 16:57
898	9	S67 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO O	2005/07/12 16:58
69S	15941	(detect\$3 sens\$3 measur\$5 examin\$5 test\$3 determin\$3 inspect\$3 anal\$5 monitor\$3 identif\$7 record\$5 meter\$5) near3 (operat\$5 near1 parameter) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 09:48
S70	14815	(detect\$3 sens\$3 measur\$5 examin\$5 test\$3 determin\$3 inspect\$3 anal\$5 monitor\$3 identif\$7 record\$5 meter\$5) near3 (operat\$5 adj1 parameter) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 10:15

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ı	5132	(assembly unit system device apparatus machine mechanism means module set instrument tool circuit equipment method) near3 (detect\$3 sens\$3 measur\$5 examin\$5 test\$3 determin\$3 inspect\$3 anal\$5 monitor\$3 identif\$7 record\$5 meter\$5) near\$ (operat\$5 adj1 parameter) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 08:55
	102	S71 and (operat\$5 adj1 parameter) near3 (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	NO .	2005/07/13 08:57
	17	S72 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO O	2005/07/13 09:49
	С	S73 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO O	2005/07/13 10:16
	632	(counter and (operating adj parameter) and (voltage near2 (change variation difference)) and (state mode status) and (IC (integrated adj circuit) \$6chip ASIC) and digital\$3) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 10:25
	144	(detect\$3 sens\$3 measur\$5 examin\$5 test\$3 determin\$3 inspect\$3 anal\$5 monitor\$3 identif\$7 record\$5 meter\$5) near3 (operat\$5 near1 parameter) and \$75	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 09:48
	4	S76 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 10:18
	2	("4,952,849").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/07/13 09:58

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S79	7309	(detect\$3 sens\$3 measur\$5) near3 (operat\$5 adj1 parameter) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 10:30
280	31	S77 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	Z O	2005/07/13 10:26
S81	414	S79 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	N O	2005/07/13 10:31
S82	17	S81 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 10:33
S83	4	S82 and digital\$3 same counter	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO O	2005/07/13 10:21
S84	0	((counter and (operating adj parameter) and (voltage near2 (change variation difference)) and (state mode status) and (IC (integrated adj circuit) \$6chip ASIC) and digital\$3).clm.) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO O	2005/07/13 10:25
S85	-	S79 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC)) same counter	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 10:34
98S	2541	measur\$5 near3 (operat\$5 adj1 parameter) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 10:30

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S87	126	S86 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	NO	2005/07/13 10:31
888	∞ .	S87 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5 specif\$5) near3 ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 10:36
688	17	S87 and (state mode status) same counter	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 10:35
06S	4	S88 and (state mode status) same counter	US-PGPUB; USPAT; EPO; IPO; DERWENT ; IBM_TDB	OR	NO	2005/07/13 10:35